

<b>Notice of References Cited</b>	Application/Control No. 10/047,717	Applicant(s)/Patent Under Reexamination KNAPP, RICHARD J.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0104022	08-2002	Jorgenson, Daniel Scott	713/201
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NON-PATENT DOCUMENTS

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